

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	171	(voltage near2 generator) and (voltage nera2 adjust\$3) and (metal with program\$4) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:50
L2	6	"327"/\$.ccls. and (voltage near2 generator) and (voltage near2 adjust\$3) and (metal with program\$4) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:40
L3	192	"327"/\$.ccls. and (voltage near2 generator) and (voltage near2 adjust\$3) and metal and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:40
L4	13	"327"/\$.ccls. and (voltage near2 generator) and (voltage near2 adjust\$3) and (metal same program\$4) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:41
L5	112	(voltage near2 generator) and (voltage near2 adjust\$3) and (metal same program\$4) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:42
L6	37	327/537.ccls. and (voltage near2 generator) and (voltage near2 adjust\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:43
L7	10	327/175.ccls. and (voltage near2 generator) and (voltage near2 adjust\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:44
L8	229	327/175.ccls. and (adjust\$3 with circuit\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:44

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L9	227	327/175.ccls. and (adjust\$3 with circuit\$3) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:45
L10	14	327/175.ccls. and (adjust\$3 with circuit\$3) and pull-up and pull-down and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:45
L11	118	327/175.ccls. and (adjust\$3 with circuit\$3) and (generat\$3 with voltage) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:47
L12	147	327/175,176.ccls. and (adjust\$3 with circuit\$3) and (generat\$3 with voltage) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:47
L13	23	327/175,176.ccls. and (adjust\$3 with circuit\$3) and (generat\$3 with voltage) and metal and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:48
L14	18	327/175.ccls. and (adjust\$3 with circuit\$3) and (generat\$3 with voltage) and metal and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:48
L15	18	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (voltage near2 generator) and (voltage nera2 adjust\$3) and (metal with program\$4) and output	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/14 09:50
S1	327	(adjust\$3 with voltage) same (test\$3 with memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/04 08:46

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S2	19	S1 and ((pullup or pull-up) with transistor\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:37
S3	10	365/201,200.ccls. and test\$3 and ((pullup or pull-up) with transistor\$1) and SRAM and ((modif\$4 or adjust\$3 or variable\$1) with bias)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/06 08:27
S7	5	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (weak with test) and SRAM and (transistor\$1 with (fuse\$1 or antifuse\$1))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
S8	51827	SRAM and memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:18
S9	15872	S8 and test\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
S10	25	S9 and ((weak adj write adj test adj mode) or WWTM)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:46
S11	325	S9 and bias near2 generat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
S12	232	S11 and driver	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47

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S13	232	S12 and voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
S14	226	S13 and transistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:48
S15	113	S14 and (pullup or pull-up)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:48
S16	98	S15 and (pulldown or pull-down)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:49
S17	69	S16 and metal\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:49
S18	3	S9 and (metal-program\$4 or (metal adj program\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:50
S19	27	test\$3 and (metal-program\$4 or (metal adj program\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:51
S20	16	S19 and memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:50

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S21	9	S20 and (bias\$3 or voltage\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:51
S22	4	(bias adj2 generator) and (metal-program\$4 or (metal adj program\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:53
S23	4966	circuit\$3 same (internal adj voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:04
S24	34	S1 and S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:54
S25	49	circuit\$3 same (internal adj voltage) same ((pullup or pull-up) with transistor\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:05
S26	16	circuit\$3 same (internal adj voltage) same ((pullup or pull-up) with transistor\$1) same ((pulldown or pull-down) with transistor\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:05
S27	2151	SRAM and ((bias or voltage) with generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:37
S28	18	S27 and adjust\$3 near5 output near5 program\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:26

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S29	42	S27 and adjust\$3 with output with program\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:26
S30	2297	SRAM and ((bias or voltage or potential) with generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:28
S31	28	S30 and adjust\$3 with output with (program\$4 or devider)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:34
S32	86	S30 and adjust\$3 same output same (program\$4 or devider)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:34
S33	5	SRAM and ((bias or voltage) with generator) with adjust\$3 with output\$3 with (program\$4 or devider or resistor)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/26 16:42
S34	50	SRAM and ((bias or voltage) with generator) and (adjust\$3 with output\$3 with (program\$4 or devider or resistor))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:11
S35	2	"6,025737".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 17:49
S36	0	2004/0119112	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 17:50

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S37	2	"20040119112"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 17:55
S38	2	"6,178113".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/07 17:55
S39	1	SRAM and (bias near2 generator) and adjust\$3 and (metal near2 program\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/07 15:19
S40	972	(metal near2 program\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/07 15:19
S41	6	S40 and (bias near2 generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/07 15:22
S42	6904	(bias near2 generator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/07 15:22
S43	48	S42 and (metal with program\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/07 15:23
S45	2	"6,735131".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:13

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S46	56	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (weak with test) and SRAM and transistor\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 07:57
S47	3770059	memory or storage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:11
S50	734	S47 and weak near3 test\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:13
S51	2	S50 and weak near3 test\$5 with default	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:14
S52	2	S50 and weak near3 test\$5 with default with high	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:14
S54	12	S50 and select\$5 with magnitude with value	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 08:52
S55	4	(bias near2 generator) with (metal near2 program\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 09:43
S56	2	"6,356139".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 09:45

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S57	18	((adjust\$4 correct\$3 modify\$3 chang\$3) with output with (bias voltage) with generat\$3 with metal) and program\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/08 09:46
S58	9	("4100437" "4978905" "5283762" "5559424" "5694076" "5818212" "5838076" "6091282" "6147479").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/09/08 09:48
S59	9	("4100437" "4978905" "5283762" "5559424" "5694076" "5818212" "5838076" "6091282" "6147479").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/09/08 11:15
S60	9	("4100437" "4978905" "5283762" "5559424" "5694076" "5818212" "5838076" "6091282" "6147479").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/09/08 11:17
S61	9	("4100437" "4978905" "5283762" "5559424" "5694076" "5818212" "5838076" "6091282" "6147479").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/09/08 11:18
S62	2	"6,025737".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/11 09:33
S63	2	"6,356139".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/11 09:34
S64	4	(WWTM or (weak adj2 write adj2 test adj2 mode)) and SRAM and (bias near2 generator) and (magnitude\$1 or voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/11 10:58
S65	5	(WWTM or (weak adj2 write adj2 test adj2 mode)) and (bias near2 generator) and (magnitude\$1 or voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/11 10:58

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S66	2	"6,192001".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/04 09:06
S67	2	"5,559745".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/04 10:28
S68	133	"365"/\$.ccls. and test\$3 and ((pullup or pull-up or (pull adj up)) with transistor\$1) and ((pulldown or pull-down or (pull adj down)) with transistor) and SRAM and ((modif\$4 or adjust\$3 or variable\$1) with (bias or voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/06 08:31
S69	2	"365"/\$.ccls. and test\$3 and ((pullup or pull-up or (pull adj up)) with transistor\$1) and ((pulldown or pull-down or (pull adj down)) with transistor) and SRAM and ((modif\$4 or adjust\$3 or variable\$1) with (bias or voltage)) and (metal near2 programming)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/06 08:32
S70	2	"365"/\$.ccls. and test\$3 and ((pullup or pull-up or (pull adj up)) with transistor\$1) and ((pulldown or pull-down or (pull adj down)) with transistor) and SRAM and ((modif\$4 or adjust\$3 or variable\$1) with (bias or voltage)) and (metal near2 program\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/06 08:32
S71	2	"6,518809".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/13 08:59
S72	2	"6,518809".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/13 16:46